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APPLICATION NO.	Fi	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/656,985 09/07/2000		Anthony M. Chiu	00-C-015	00-C-015 2236		
30425	7590	05/13/2002				
STMICROE	LECTR	ONICS, INC.	EXAMINER			
MAIL STATI	RONICS	DRIVE	PAREKH, NITIN			
CARROLLTON, TX 75006				ART UNIT	PAPER NUMBER	
				2811		
				DATE MAILED: 05/13/2002		

Please find below and/or attached an Office communication concerning this application or proceeding.

·		Application No.	Applicant(s)				
				/			
	Office Action Summany	09/656,985	CHIU, ANTHONY M.				
Office Action Summary		Examiner	Art Unit				
	- The MAILING DATE of this communication app	Nitin Parekh	2811				
Period for	• •	dears on the cover sheet with the c	orrespondence address				
THE N - Extense after S - If the p - If NO - Failure - Any re	ORTENED STATUTORY PERIOD FOR REPL' MAILING DATE OF THIS COMMUNICATION. sions of time may be available under the provisions of 37 CFR 1.1: 60X (6) MONTHS from the mailing date of this communication. Deriod for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period of the to reply within the set or extended period for reply will, by statute the ply received by the Office later than three months after the mailing the patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be tin y within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from t, cause the application to become ABANDONE	nely filed /s will be considered timely. I the mailing date of this communication. ED (35 U.S.C. § 133).				
1)🛛	Responsive to communication(s) filed on 23.	<u>January 2002</u> .					
2a) <u></u> □	This action is FINAL . 2b)⊠ Th	nis action is non-final.					
3)	Since this application is in condition for allows						
Disposition	closed in accordance with the practice under on of Claims	Ex parte Quayle, 1935 C.D. 11, 4	453 O.G. 213.				
4)⊠	Claim(s) <u>1-18</u> is/are pending in the application	1.					
4	4a) Of the above claim(s) <u>8-18</u> is/are withdrawi	n from consideration.					
5)[Claim(s) is/are allowed.						
6)⊠	Claim(s) <u>1-7</u> is/are rejected.						
7) 🗌	Claim(s) is/are objected to.						
	Claim(s) are subject to restriction and/o	or election requirement.					
	The specification is objected to by the Examine	er.					
	The drawing(s) filed on is/are: a)□ acce		aminer.				
·	Applicant may not request that any objection to th	•					
11) 🔲 🏻	he proposed drawing correction filed on	_ is: a)□ approved b)□ disappro	oved by the Examiner.				
	If approved, corrected drawings are required in re	ply to this Office action.					
12)□ 1	he oath or declaration is objected to by the Ex	kaminer.					
Priority u	nder 35 U.S.C. §§ 119 and 120						
13)	Acknowledgment is made of a claim for foreign	n priority under 35 U.S.C. § 119(a	a)-(d) or (f).				
a)[☐ All b) ☐ Some * c) ☐ None of:						
	1. Certified copies of the priority document	s have been received.					
	2. Certified copies of the priority documents have been received in Application No						
	3. Copies of the certified copies of the prio application from the International Buee the attached detailed Office action for a list	reau (PCT Rule 17.2(a)).	Ğ	,			
	cknowledgment is made of a claim for domest	·					
	☐ The translation of the foreign language pro	, , ,					
	cknowledgment is made of a claim for domest						
		A) []	ov (DTO 442) Damas Na/a)				
2) Notice	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449) Paper No(s) _	5) Notice of Informal	y (PTO-413) Paper No(s) Patent Application (PTO-152)				
J.S. Patent and Tra	ademark Office						

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Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

1. Claim 6 is rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

Claim 6, line 6 cites: "mounting the integrated circuits in contact with each other".

However, the description in the specification (page 7, line 30; page 9, line 3; page 12, lines 2-4) and Figures 1 and 4 show the sensor segments/packages (104a, 104b, /402a, 402b, etc.) being spaced by a kerf/saw width.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-5 and 7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yamawaki et al (US Pat. 4894707) in view of Weiblen et al (US Pat. 6300169), Kunii et al (US Pat. 6252252) and further in view of Yoshihara et al (US Pat. 6255741) and Chan et al (US Pat. 6171879).

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Regarding claims 1-4, Yamawaki et al disclose a method of forming an image/photo sensor comprising:

- an integrated circuit/photosensor chip (1 in Fig. 5f) having a portion remaining exposed after packaging/encapsulating
- a plurality of conventional leads (6 in Fig. 5f) adapted for further mounting/soldering, the packaging method further comprising:
- affixing the IC chip/die to a lead frame (Fig. 5c; Col. 2, line 66)
- connecting the IC die/chip to selected portions of the lead frame with bond wires,
 (Fig. 5d; Col. 2, line 67)and
- encapsulating a portion of the lead frame and the die except for the exposed region where the exposed region of the die remains exposed to the external light, the encapsulating step comprising: mounting the lead frame, die and the bond wires in a mold (21/22 in Fig. 5e) with a portion of the mold in contact with the exposed region of the IC die to prevent the encapsulating material from adhering to the exposed region of the IC die (Fig. 5e; Col. 3, line 50)

(Fig. 5f; Fig. 5a-e; Col. 2, line 50- Col. 3, line 50).

Yamawaki et al fail to specify using a linear array of photosensor IC being adapted for soldering the respective leads to a circuit board.

However, it is conventional in chip/leadframe packaging technology art to use the substrates such as lead frame, circuit board, etc. where a plurality of IC/an array are

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wire bonded and subsequently being soldered to a circuit board to improve the cycle time and production yield.

Weiblen et al teach using a linear array of ICs (2 in Fig. 1) wire bonded on a conventional lead frame (Col. 2).

Kunii et al teach using a conventional circuit board where the leads of a plurality/array of optical IC devices are soldered to a circuit board (48 in Fig. 9; Col. 12, line 3). Kunii et al further teach using a variety of mold configurations including a mold cavity structure such that one surface of the mold cavity is a sloped surface receiving bond wires when the lead frame with the IC die is mounted in the mold (Fig. 14; Col. 12, line 51).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a linear array of photosensors being adapted for soldering the respective leads to a circuit board and a step of mounting the lead frame and die such that one surface of the mold cavity is a sloped surface receiving bond wires to improve the optical reflection, cycle time and production yield using Weiblen et al and Kunii et al's processes in Yamawaki et al's method.

Regarding claim 5, Yamawaki et al in view of Weiblen et al and Kunii et al fail to specify the separation distance between the mounted dice being equal to a kerf width for a singulation saw used in separating the packaged ICs.

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It is a matter of a design choice in chip packaging and encapsulation technology art to select the dimensions such as kerf spacing, encapsulation width/length, saw/blade thickness, etc. to achieve the desired package dimensions.

Yoshihara et al teach using a saw where the width of the saw is slightly smaller than the kerf spacing/width of the devices (Fig. 12; Col. 9, line 3).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate the separation distance between the mounted dice being equal to a kerf width for a singulation saw used in separating the packaged devices to reduce overall package dimensions and weight using Yoshihara et al's teaching in Yamawaki et al's method in view of Weiblen et al and Kunii et al.

Regarding claim 7, Yamawaki et al in view of Weiblen et al and Kunii et al fail to specify the step of soldering where the leads on the other side of soldered leads are being in floating contact with the conductive structures on the board to facilitate adjustment and removal of the ICs.

Chan et al teach using conventional floating contacts (26/26' in Fig. 2-5) with conductive layers/structure on the substrate to improve flexibility in connection and reduce stress/strain in an integrated sensor device (Col. 5, line 10- Col. 6, line 43).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a step of soldering where the leads on the other side of soldered leads are being in floating contact with the conductive structures

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on the board to facilitate adjustment and removal of the IC Chan et al's teaching in

Yamawaki et al's method in view of Weiblen et al and Kunii et al.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Nitin Parekh whose telephone number is 703-305-3410.

The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Tom Thomas can be reached on 703-308-2772. The fax phone numbers

for the organization where this application or proceeding is assigned are 703-308-7722

for regular communications and 703-308-7722 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or

proceeding should be directed to the receptionist whose telephone number is 703-306-

3431.

Nitin Parekh

NP

05-02-02

Staven Loke Primory Examinar

Steven Loke